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Responsible committee: W/- Miscellaneous Standards - Consumer Products and Services

Interested committees:

Title: BS EN IEC 63541 Lithium tantalate and lithium niobate crystal for surface acoustic wave (SAW) device applications - Specifications and measuring method

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- iii) requires additional national guidance or information

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Introduction

This draft standard is based on national and international discussions. Your comments on this draft are invited and will assist in the preparation of the consequent standard.

For international standards, comments will be reviewed by the relevant UK national committee before sending the consensus UK vote and comments to the international committee, which will then decide appropriate action. If the international standard is approved, it is usual for the text to be published as a British Standard.

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UK Vote

Please indicate whether you consider the UK should submit a negative (with supporting technical reasons) or positive vote on this draft. Please indicate if you are aware of any reason why this draft standard should not be published as a British Standard.

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Template for comments and secretariat observations

Date: xx/xx/20xx	Document: ISO/DIS xxxx
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1	2	(3)	4	5	(6)	7
MB	Clause No./ Subclause No./Annex (e.g. 3.1)	Paragraph/Figure/ Table/Note	Type of comment	Commend (justification for change) by the MB	Proposed change by the MB	Secretariat observations on each comment submitted
	3.1	Definition 1	ed	Definition is ambiguous and needs clarifying.	Amend to read '...so that the mains connector to which no connection...'	
	6.4	Paragraph 2	te	The use of the UV photometer as an alternative cannot be supported as serious problems have been encountered in its use in the UK.	Delete reference to UV photometer.	



49/1458A/CD

COMMITTEE DRAFT (CD)

PROJECT NUMBER:

IEC 63541 ED1

DATE OF CIRCULATION:

2024-05-10 (2024-05-03)

CLOSING DATE FOR COMMENTS:

2024-07-26

SUPERSEDES DOCUMENTS:

49/1437A/NP, 49/1450A/RVN

IEC TC 49 : PIEZOELECTRIC, DIELECTRIC AND ELECTROSTATIC DEVICES AND ASSOCIATED MATERIALS FOR FREQUENCY CONTROL, SELECTION AND DETECTION

SECRETARIAT:

JAPAN

SECRETARY:

MR MASANOBU OKAZAKI

OF INTEREST TO THE FOLLOWING COMMITTEES:

OF INTEREST TO THE FOLLOWING COMMITTEES:

Other TC/SCs are requested to indicate their interest, if any, in this CD to the secretary.

FUNCTIONS CONCERNED:

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☐ ENVIRONMENT

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TITLE:

Lithium tantalate and lithium niobate crystal for surface acoustic wave (SAW) device applications - Specifications and measuring method

NOTE FROM TC/SC OFFICERS:

This 'A' version replaced 49/1458/CD circulated on 2024-05-03 due to error in cover page. No modification in content and closing date for comments remains the same.

The title of the project was modified.

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

LITHIUM TANTALATE AND LITHIUM NIOBATE CRYSTALS FOR SURFACE ACOUSTIC WAVE (SAW) DEVICE APPLICATIONS – SPECIFICATIONS AND MEASURING METHODS

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IEC 63541 has been prepared by IEC technical committee 49: Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection. It is an International

140 Standard.

141 The text of this International Standard is based on the following documents:

CDV	Poll report

142 Full information on the voting for its approval can be found in the report on voting indicated in the above
143 table.

144 The language used for the development of this International Standard is English

145 This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance
146 with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at
147 www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in
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- 154 • replaced by a revised edition, or
- 155 • amended